

JEOL PROPOSES A NEW ANALYTICAL TEM

JEM | 2800

HIGH THROUGHPUT ELECTRON MICROSCOPE



Quick Turn Around Time

Full automation

- Auto contrast / brightness
- Auto sample height control
- Auto crystal orientation alignment
- Auto focus control
- Auto stigmator control

All-in-one for easy use
by anyone

www.jeol.com



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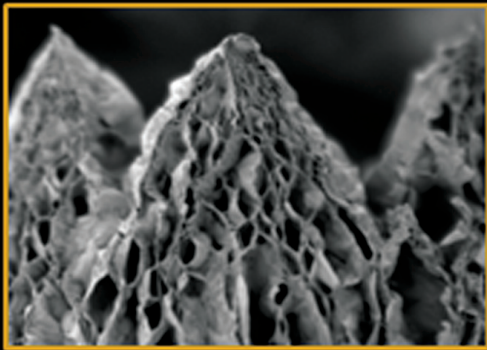


JSM-7800F *Prime*

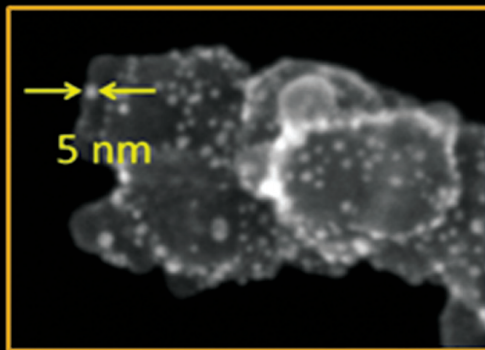


SUB-NANOMETRIC IMAGING & NANOMETRIC ANALYSIS

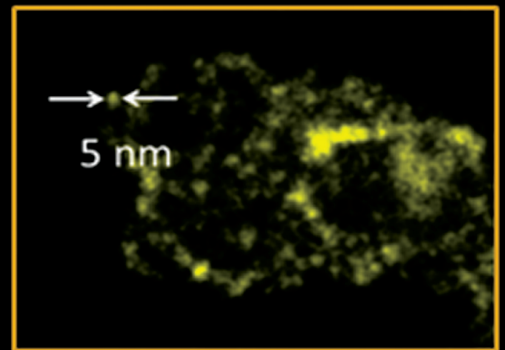
Resolution: 0.7nm from 30kV to 1kV



Graphene (80V)



EDS analysis of nanoparticles



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